Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/005,043	YEH ET AL.	
Examiner	Art Unit	
Jungwon Chang	2154	

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Class	Subclass	Date	Examiner
709	250	9/1/2006	JWC
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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